

Octal Transparent Latch, 3-State

CD54/74AC/ACT373 - Non-Inverting CD54/74AC/ACT533 - Inverting

Type Features:

- Buffered inputs
- Typical propagation delay: 4.3 ns @ V_{CC} = 5 V, T_A = 25° C, C_L = 50 pF

FUNCTIONAL DIAGRAM

The RCA-CD54/74AC373 and CD54/74AC533 and the CD54/74ACT373 and CD54/74ACT533 octal transparent 3-state latches use the RCA ADVANCED CMOS technology. The outputs are transparent to the inputs when the Latch Enable (LE) is HIGH. When the Latch Enable (LE) goes LOW, the data is latched. The Output Enable (OE) controls the 3-state outputs. When the Output Enable (OE) is HIGH, the outputs are in the high-impedance state. The latch operation is independent of the state of the Output Enable.

The CD74AC/ACT373 and CD74AC/ACT533 are supplied in 20-lead dual-in-line plastic packages (E suffix) and in 20-lead dual-in-line small-outline plastic packages (M suffix). Both package types are operable over the following temperature ranges: Commercial (0 to 70°C); Industrial (-40 to +85°C); and Extended Industrial/Military (-55 to +125°C).

The CD54AC/ACT373 and CD54AC/ACT533, available in chip form (H suffix), are operable over the -55 to +125°C temperature range.

Family Features:

- Exceeds 2-kV ESD Protection MIL-STD-883, Method 3015
- SCR-Latchup-resistant CMOS process and circuit design
- Speed of bipolar FAST*/AS/S with significantly reduced power consumption
- Balanced propagation delays
- AC types feature 1.5-V to 5.5-V operation and balanced noise immunity at 30% of the supply
- ± 24-mA output drive current
 - Fanout to 15 FAST* ICs
 - Drives 50-ohm transmission lines

TRUTH TABLE

Output Enable	Latch Enable	Data	AC/ACT373 Output	AC/ACT533 Output
L	н	н	н	L
Ł	н	L	L	н
L	L	1	[L	Ħ
L	L	h	j н	L
н,	×	×	Z	Z

Note:

- L = Low voltage level
- H = High voltage level
- t = Low voltage level one set-up time prior to the high to low latch enable transition
- h = High voltage level one set-up time prior to the high to low latch enable transition.
- X = Don't Care
- Z = High Impedance State

This data sheet is applicable to the CD54/74AC373, CD54/74ACT373, and CD54ACT533. The CD74AC533 and CD74ACT533 were not acquired from Harris Semiconductor.

^{*}FAST is a Registered Trademark of Fairchild Semiconductor Corp.

MAXIMUM RATINGS, Absolute-Maximum Values:	
DC SUPPLY-VOLTAGE (V∞)	-0.5 to 6 V
DC INPUT DIODE CURRENT, I_{ik} (for $V_i < -0.5$ V or $V_i > V_{cc} + 0.5$ V)	+20 mA
$_{\rm OC}$ OUTPUT DIODE CURRENT, $_{\rm loc}$ (for $_{\rm V_0}$ < -0.5 V or $_{\rm V_0}$ > $_{\rm V_{cc}}$ + 0.5 V)	±50 mA
\sim DC OUTPUT SOURCE OR SINK CURRENT per Output Pin, I_0 (for $V_0 > -0.5$ V $_0$	or $V_0 < V_{cc} + 0.5 \text{ V}$
DC Vcc or GROUND CURRENT (Icc or Igno)	+100 mA*
POWER DISSIPATION PER PACKAGE (PD):	
For T _A = -55 to +100°C (PACKAGE TYPE E)	500 mW
For $I_A = +100$ to $+125$ °C (PACKAGE TYPE E)	Derate Linearly at 8 mW/°C to 300 mW
For $I_A = -55$ to $+70$ °C (PACKAGE TYPE M)	400 mW
For $I_A = +70$ to $+125$ °C (PACKAGE TYPE M)	Derate Linearly at 6 mW/°C to 70 mW
OPERATING-TEMPERATURE RANGE (TA)	
STORAGE TEMPERATURE (Isto)	65 to +150°C
LEAU TEMPERATURE (DURING SOLDERING):	
At distance 1/16 \pm 1/32 in. (1.59 \pm 0.79 mm) from case for 10 s maximum	+265°C
Unit inserted into PC board min. thickness 1/16 in. (1.59 mm) with solder conta	acting lead tips only +300°C
*For up to 4 outputs per device; add \pm 25 mA for each additional output.	
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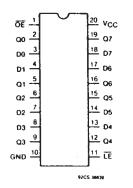
RECOMMENDED OPERATING CONDITIONS:

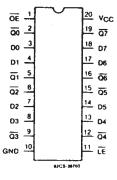
For maximum reliability, normal operating conditions should be selected so that operation is always within the following ranges:

CHARACTERISTIC	LI	LINUTO		
	MIN.	MAX.	UNITS	
Supply-Voltage Range, V∞*:		1	 	
(For T _A = Full Package-Temperature Range)	•		1	
AC Types	1.5	5.5	·	
ACT Types	4.5	5.5	V	
DC Input or Output Voltage, V _I , V _O	0	V _{cc}	V	
Operating Temperature, T _A	-55	+125	°C	
Input Rise and Fall Slew Rate, dt/dv	-			
at 1.5 V to 3 V(AC Types)	0	50	ns/V	
at 3.6 V to 5.5 V(AC Types)	Ō	20	ns/V	
at 4.5 V to 5.5 V(ACT Types)	. 0	10	ns/V	

^{*}Unless otherwise specified, all voltages are referenced to ground.

TERMINAL ASSIGNMENT DIAGRAMS





CD54/74AC373, CD54/74ACT373

CD54/74AC533, CD54/74ACT533

Technical Data __

CD54/74AC373, CD54/74AC533 CD54/74ACT373, CD54/74ACT533

STATIC ELECTRICAL CHARACTERISTICS: AC Series

						AMBIENT	TEMPE	RATURE	(T _A) - °(
CHARACTERIST	ICS	TEST CO	NDITIONS	V _{cc}	+:	25	-40 t	o +85	-55 to	+125	UNITS
		V ₁ (V)	l _o (mA)	(V)	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
High-Level Input				1.5	1.2	_	1.2		1.2		
Voltage	VIH			3	2.1		2.1		2.1		V
		,		5.5	3.85	_	3.85	_	3.85		
Low-Level Input				1.5	_	0.3	_	0.3		0.3	
Voltage V				3	_	0.9	_	0.9	<u> </u>	0.9	V
				5.5	-	1.65	_	1.65	-	1.65	
High-Level Output			-0.05	1.5	1.4	-	1.4	_	1.4		
Voltage	V _{он}	VIH	-0.05	3	2.9		2.9	_	2.9]
		or	-0.05	4.5	4.4	_	4.4	<u> </u>	4.4	_]
		V _{IL}	-4	3	2.58	_	2.48	_	2.4	_] v
			-24	4.5	3.94	_	3.8		3.7]
		(-75	5.5		_	3.85	_	T -	_	
		#, *	-50	5.5	<u> </u>		_	_	3.85	_]
Low-Level Output			0.05	1.5	1 –	0.1		0.1	_	0.1	
Voltage	V_{OL}	ViH	0.05	3	_	0.1	-	0.1		0.1]
		or	0.05	4.5	-	0.1		0.1		0.1]
		V _{IL}	12	3		0.36	_	0.44		0.5	V
			24	4.5	-	0.36	_	0.44		0.5	
		(75	5.5	_	_		1.65	_	-]
		#, * {	50	5.5	_	_	_	_	_	1.65	1
Input Leakage Current	l _t	V _{cc} or GND		5.5	_	±0.1	_	±1	_	±1	μА
3-State Leakage Current	loz	Viei									
	-	or V _{IL}									
		V _o =		5.5	_	±0.5	_	±5	_	±10	μΑ
		or									
		GND		<u> </u>				 	_		-
Quiescent Supply Current, MSI	Icc	V _∞ or GND	0	5.5	_	8	_	80	_	160	μΑ

[#]Test one output at a time for a 1-second maximum duration. Measurement is made by forcing current and measuring voltage to minimize power dissipation

power dissipation.
*Test verifies a minimum 50-ohm transmission-line-drive capability at +85°C, 75 ohms at +125°C.

STATIC ELECTRICAL CHARACTERISTICS: ACT Series

						AMBIEN	T TEMP	ERATUR	E (T _A) - °	С	
CHARACTERIST	ics	TEST CO	NDITIONS	V _{cc}	+	25	-40 1	to +85	-55 t	o +125	UNITS
		V, (V)	I _o (mA)	(V)	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
High-Level Input Voltage	ViH			4.5 to 5.5	2	-	2	_	2	_	v
Low-Level Input Voltage	V _{IL}			4.5 to 5.5	_	0.8	_	0.8	_	0.8	V
High-Level Output		V _{IH}	-0.05	4.5	4.4		4.4	_	4.4	<u> </u>	
Voltage	V _{OH}	or V _{IL}	-24	4.5	3.94	-	3.8		3.7	† –] ,
		#, * {	-75	5.5	_	_	3.85	_	_		1 '
			-50	5.5		_	<u> </u>	_	3.85	_	1
Low-Level Output		V _{IH}	0.05	4.5	_	0.1	-	0.1	_	0.1	
Voltage	Vol	or V _{IL}	24	4.5		0.36	_	0.44	_	0.5] _v
	:	#, * {	75	5.5	-	_	l —	1.65			1 *
			50	5.5	-	_	_		_	1.65	1
Input Leakage Current	l,	V _{cc} or GND		5.5	_	±0.1	_	±1	_	±1	μΑ
3-State Leakage Current	loz	V _{IH}									
		V _{IL}									
		V _o = V _{cc}		5.5	_	±0.5	_	±5	_	±10	μΑ
		or GND									
Quiescent Supply Current, MSI	Icc	V _∞ or GND	0	5.5	_	8		80		160	μΑ
Additional Quiescent S Current per Input Pi TTL Inputs High 1 Unit Load	Supply n Δl_{cc}	V _{cc} -2.1		4.5 to 5.5	_	2.4		2.8	_	3	mA

[#]Test one output at a time for a 1-second maximum duration. Measurement is made by forcing current and measuring voltage to minimize power dissipation.

*Test verifies a minimum 50-ohm transmission-line-drive capability at +85°C, 75 ohms at +125°C.

ACT INPUT LOADING TABLE

INPUT	UNIT LOAD*						
INFUI	ACT373	ACT533					
ŌE	0.87	0.87					
Dn	0.5	0.5					
ĹĒ	0.8	0.8					

*Unit load is ΔI_{CC} limit specified in Static Characteristics Chart, e.g., 2.4 mA max. @ 25°C.

PREREQUISITE FOR SWITCHING: AC Series

			AMBI	ENT TEMPE	UNITS		
CHARACTERISTICS	SYMBOL	V _{cc} (V)	-40 to +85			-55 to +125	
		(V)	MIN.	MAX.	MIN.	MAX.	
LE Pulse Width	tw	1.5 3.3*	44 4.9 3.5	_	50 5.6 4	_	ns
Setup Time Data to LE	tsu	5† 1.5 3.3 5	2 2 2		2 2 2		ns
Hold Time Data to LE	t _H	1.5 3.3 5	33 3.7 2.6	=	38 4.2 3	_ 	ns

*3.3 V: min. is @ 3 V †5 V: min. is @ 4.5 V

SWITCHING CHARACTERISTICS: AC Series; t,, t, = 3 ns, C, = 50 pF

			AMBI	ENT TEMPE	RATURE (T	'A) - °C	_
CHARACTERISTICS	SYMBOL	V _{cc}	-40 t	o +85	-55 to	+125	UNITS
		(V)	MIN.	MAX.	MIN.	MAX.	
Propagation Delays: Data to Qn 373	t _{PLH} t _{PHL}	1.5 3.3* 5†	3.1 2.2	96 10.8 7.7	— 3 2.1	106 11.9 8.5	ns
533	tpLH tpHL	1.5 3.3 5	3.8 2.7	119 13.4 9.5	3.7 2.6	131 14.7 10.5	ns
LE on Qn 373	t _{PLH} t _{PHL}	1.5 3.3 5	4.3 3.1	136 15.2 10.9	4.2 3	150 16.8 12	ns
533	telн teнl	1.5 3.3 5	 4.3 3.1	136 15.3 10.9	4.2 3	150 16.8 12	ns
Output Enable Times	tezu tezh	1.5 3.3 5	4.1 2.7	119 14.4 9.5	4 2.6	131 15.8 10.5	ns
Output Disable Times	tplz tpHz	1.5 3.3 5	3.7 3	131 13.1 10.5	3.6 2.9	144 14.4 11.5	ns
Power Dissipation Capacitance	C _{PD} §		63	Тур.	63	Тур.	pF
Min. (Valley) V _{он} During Switching of Other Outputs (Output Under Test Not Switching)	V _{онv} See Fig. 1	5		4 Typ. @ 25°C			V
Max. (Peak) V _{OL} During Switching of Other Outputs (Output Under Test Not Switching)	V _{OLP} See Fig. 1	5		1 Typ. @ 25°C			v
Input Capacitance	Cı	_	I –	10		10	pF
3-State Output Capacitance	Co			15		15	pF

*3.3 V; min. is @ 3.6 V max. is @ 3 V

†5 V: min. is @ 5.5 V max. is @ 4.5 V §CPD is used to determine the dynamic power consumption, per latch. $P_D = V_{CC}^2$ f_i $(C_{PD} + C_L)$ where f_i = input frequency C_L = output load capacitance

 V_{cc} = supply voltage.

PREREQUISITE FOR SWITCHING: ACT Series

			AMBI	1 ,			
CHARACTERISTICS	SYMBOL	V _{cc} (V)	-40 to +85		-55 to +125		UNITS
			MIN.	MAX.	MIN.	MAX.	
TE Pulse Width	tw	5†	3.6	· -	4	_	ns
Setup Time Data to LE	tsu	5	2	_	2	_	ns
Hold Time Data to LE	t _H	5	2.7	_	3		ns

†5 V: min. is @ 4.5 V

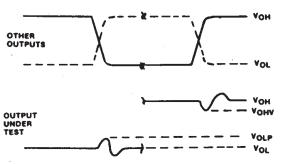
SWITCHING CHARACTERISTICS: ACT Series; t,, t, = 3 ns, C, = 50 pF

			AMBI	ENT TEMPI	ERATURE (T _A) -°C	
CHARACTERISTICS	SYMBOL	V _{cc} (V)		o +85	-55 to	UNITS	
		(*)	MIN.	MAX.	MIN.	MAX.	1
Propagation Delays: Data to Qn 373	t _{PLH}	F.1	2.7	9.5	2.6	10.4	
533	t _{PHL}	5†	3	10.4	2.9	11.4	ns
LE to Qn 373 533	t _{PLH}	5	3.1	11.4	3	12.5	ns
Output Enable Times	t _{PZL}	5	3.5	12.3	3.4	13.5	ns
Output Disable Times	t _{PLZ} t _{PHZ}	5	3.2	11.4	3.1	12.5	ns
Power Dissipation Capacitance	C _{PD} §		63 1	Гур.	63 Typ.		pF
Min. (Valley) V _{OH} During Switching of Other Outputs (Output Under Test Not Switching)	V _{OHV} See Fig. 1	5	4 Typ. @ 25°C				v
Max. (Peak) Vol During Switching of Other Outputs (Output Under Test Not Switching)	V _{OLP} See Fig. 1	5		1 Typ. @ 25°C			٧
Input Capacitance	C ₁	_	_	10	_	10	pF
3-State Output Capacitance	Co	_	_	15	_	15	pF

†5 V: min. is @ 5.5 V max. is @ 4.5 V

 V_{cc} = supply voltage.

PARAMETER MEASUREMENT INFORMATION



NOTES:

- 1. VOHY AND VOLP ARE MEASURED WITH RESPECT TO A GROUND REFERENCE NEAR THE OUTPUT UNDER TEST.
- 2. INPUT PULSES HAVE THE FOLLOWING CHARACTERISTICS:
- PRR ≤ 1 MHz, t = 3 no, t = 3 no, SKEW 1 no.

 3. R.F. FIXTURE WITH 700-MHz DESIGN RULES REQUIRED. IC SHOULD BE SOLDERED INTO TEST BOARD AND BYPASSED WITH 0.1 JF CAPACITOR, SCOPE AND PROBES REQUIRE 700-MHz BANDWIDTH.

9205-42406

Fig. 1 - Simultaneous switching transient waveforms.

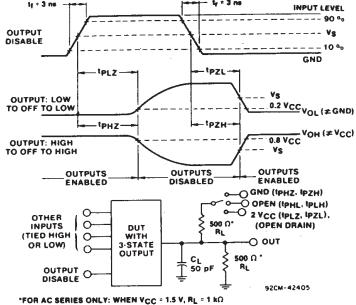


Fig. 2 - Three-state propagation delay waveforms and test circuit.

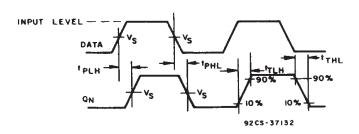


Fig. 3 - Data to Qn output propagation delays and output transistion times.

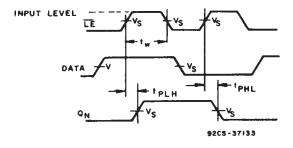
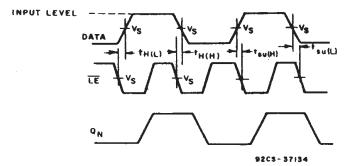


Fig. 4 - Latch enable propagation delays.



	CD54/74AC	CD54/74ACT
Input Level	Vcc	3 V
Input Switching Voltage, Vs	0.5 V _{cc}	1.5 V
Output Switching Voltage, Vs	0.5 V _{cc}	0.5 V _{cc}

Fig. 5 - Latch enable prerequisite times.





17-Mar-2017

PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty		Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Samples
CD54AC373F3A	ACTIVE	CDIP	J	20	1	(2) TBD	(6) A42	(3) N / A for Pkg Type	-55 to 125	CD54AC373F3A	c 1
											Samples
CD54ACT373F3A	ACTIVE	CDIP	J	20	1	TBD	A42	N / A for Pkg Type	-55 to 125	CD54ACT373F3A	Samples
CD74AC373E	ACTIVE	PDIP	N	20	20	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-55 to 125	CD74AC373E	Samples
CD74AC373M	ACTIVE	SOIC	DW	20	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	AC373M	Samples
CD74AC373M96	ACTIVE	SOIC	DW	20	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	AC373M	Samples
CD74AC373MG4	ACTIVE	SOIC	DW	20	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	AC373M	Samples
CD74ACT373E	ACTIVE	PDIP	N	20	20	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-55 to 125	CD74ACT373E	Samples
CD74ACT373EE4	ACTIVE	PDIP	N	20	20	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-55 to 125	CD74ACT373E	Samples
CD74ACT373M	ACTIVE	SOIC	DW	20	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	ACT373M	Samples
CD74ACT373M96	ACTIVE	SOIC	DW	20	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	ACT373M	Samples
CD74ACT373M96E4	ACTIVE	SOIC	DW	20	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	ACT373M	Samples
CD74ACT373MG4	ACTIVE	SOIC	DW	20	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	ACT373M	Samples

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

TBD: The Pb-Free/Green conversion plan has not been defined.

⁽²⁾ Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.





17-Mar-2017

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes. **Pb-Free** (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead/Ball Finish Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

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OTHER QUALIFIED VERSIONS OF CD54AC373, CD54ACT373, CD74AC373, CD74ACT373:

Catalog: CD74AC373, CD74ACT373

Military: CD54AC373, CD54ACT373

NOTE: Qualified Version Definitions:

- Catalog TI's standard catalog product
- Military QML certified for Military and Defense Applications

PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





	Dimension designed to accommodate the component width
	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CD74AC373M96	SOIC	DW	20	2000	330.0	24.4	10.8	13.0	2.7	12.0	24.0	Q1
CD74ACT373M96	SOIC	DW	20	2000	330.0	24.4	10.8	13.0	2.7	12.0	24.0	Q1

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*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CD74AC373M96	SOIC	DW	20	2000	367.0	367.0	45.0
CD74ACT373M96	SOIC	DW	20	2000	367.0	367.0	45.0

14 LEADS SHOWN



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. This package is hermetically sealed with a ceramic lid using glass frit.
- D. Index point is provided on cap for terminal identification only on press ceramic glass frit seal only.
- E. Falls within MIL STD 1835 GDIP1-T14, GDIP1-T16, GDIP1-T18 and GDIP1-T20.

N (R-PDIP-T**)

PLASTIC DUAL-IN-LINE PACKAGE

16 PINS SHOWN



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Falls within JEDEC MS-001, except 18 and 20 pin minimum body length (Dim A).
- The 20 pin end lead shoulder width is a vendor option, either half or full width.





SOIC



NOTES:

- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.43 mm per side.
- 5. Reference JEDEC registration MS-013.



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NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



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NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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